

UNITED STATES PATENT AND TRADEMARK OFFICE  
**CERTIFICATE OF CORRECTION**

PATENT NO. : 6,878,440 B1  
DATED : April 12, 2005  
INVENTOR(S) : Yamanaka Keizo

Page 1 of 2

It is certified that error appears in the above-identified patent and that said Letters Patent is hereby corrected as shown below:

Title page.

Item [57], ABSTRACT.

Line 3, insert the word -- the -- after "between" and before "substrate"

Column 3.

Line 23, "y-ray" should be shown as --  $\gamma$ -ray --

Column 8.

Lines 7-10, "Also, an electron-beam degradable material may be used in combination with a non electron-beam degradable or electron cross-linkable material if a film of the combination is not damaged by electron beam irradiation." should be shown as -- Also a film of an electron-beam degradable material can be made so as not to be damaged by electron-beam irradiation, for example, by combining the material with a non electron-beam degradable or electron cross-linkable material, and, therefore such materials can be used under such irradiation conditions. --

Column 11.

Line 6, "ement" should be shown as -- treatment --

Column 14.

Line 59, "CITE" should be shown as -- CTFE --

Line 60, "PTFE" should be shown as -- ETFE --

Column 17.

Line 2 "IOA/FC-22 11=80/20" should be shown as -- IOA/FC-2211=80/20 --

Lines 9-10, "IOA/FC-221" should be shown as -- IOA/FC-2211 --

Line 11, "80/20/0.4" should be shown as -- 80/20/0.4 --

Line 15, "ml/cm<sup>2</sup>" should be shown as -- mJ/cm<sup>2</sup> --

Column 18.

Line 36, "nm/min" should be shown as -- mm/min --

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**Column 23,**

Line 26, "BA/AA=30)" should be shown as -- BA/AA=30/70) --

Signed and Sealed this

Twenty-eighth Day of June, 2005



JON W. DUDAS  
*Director of the United States Patent and Trademark Office*